

ICDD 2008 PRODUCT DEVELOPMENTS: DDView+ and Sieve+

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DDView+ is ICDD's powerful data mining and viewing XRD software. It has the ability to search through the entire ICDD PDF-4+ database using numerous permutations of XRD criteria. Once the desired search patterns are achieved, DDView+ can view extensive XRD information including diffraction, physical, crystal, and bibliographic data. In addition, these patterns have advanced tools such as simulated x-ray diffraction patterns, electron diffraction patterns, and 3D structures. DDView+ can be greatly extended through the use of Sieve+, ICDD's search-index software plug-in. Using highly optimized algorithms, Sieve+ can rapidly match the d-spacing lines of user's experimental data to fit patterns in the PDF-4+ database.

To enhance the value of DDView+ and Sieve+, ICDD has incorporated many new developments for the 2008 product release. New display fields have been added to both DDView+ and Sieve+ search results. Graphing composition fields has been extended to include the individual elements of patterns. The PDF Cards have been updated to display PD3 patterns (a recent ICDD initiative for incorporating nano-crystalline, semi-crystalline, and amorphous materials into the PDF-4+ database). Also, Sieve+ for the PDF-2 has been upgraded to allow user's full experimental data to be imported. These are just some of the value-added developments designed to make both DDView+ and Sieve+ more functional and powerful for 2008.